

<b>Notice of References Cited</b>	Application/Control No. 10/634,047	Applicant(s)/Patent Under Reexamination MAIER ET AL.	
	Examiner Mark L. Berch	Art Unit 1624	Page 1 of 1

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	K	US-			
	L	US-			
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	O	WO 2004028524 A1 ✓	04-2004	World Intellect	YASUDA et al.	A61K 31/155
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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